MOSFET – Power, Single, N-Channel, μ8FL 30 V, 38 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- CPU Power Delivery
- DC-DC Converters

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

_	_		Г		
Para	Symbol	Value	Unit		
Drain-to-Source Volt	Drain-to-Source Voltage				V
Gate-to-Source Volta	V_{GS}	±20	V		
Continuous Drain Current R _{0JA}		T _A = 25°C	I _D	11.7	Α
(Note 1)		T _A = 80°C		8.5	
Power Dissipation R _{0JA} (Note 1)		T _A = 25°C	P _D	2.06	W
Continuous Drain		T _A = 25°C	I _D	15.8	Α
Current R _{θJA} ≤ 10 s (Note 1)		T _A = 80°C		11.4	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T _A = 25°C	P _D	3.73	W
Continuous Drain	State	$T_A = 25^{\circ}C$	I _D	7.2	Α
Current R _{θJA} (Note 2)		T _A = 80°C		5.2	
Power Dissipation R _{θJA} (Note 2)		T _A = 25°C	P _D	0.78	W
Continuous Drain		T _C = 25°C	I _D	38	Α
Current R _{θJC} (Note 1)		T _C =80°C		27	
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C	P _D	21.5	W
Pulsed Drain Current	$T_A = 25^{\circ}$	°C, t _p = 10 μs	I _{DM}	68	Α
Current Limited by Pa	ckage	T _A = 25°C	I _{Dmax}	70	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to +150	°C
Source Current (Body Diode)			I _S	19	Α
Drain to Source DV/DT			dV/d _t	7.0	V/ns
Single Pulse Drain-to-Source Avalanche Energy ($T_J = 25^{\circ}C$, $V_{GS} = 10$ V, $I_L = 4$ A _{pk} , $L = 0.1$ mH, $R_{GS} = 25$ Ω) (Note 3)			E _{AS}	22	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T _L	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

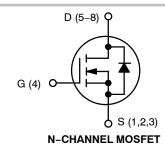
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.



ON Semiconductor®

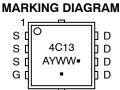
http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX	
30 V	9.4 mΩ @ 10 V	38 A	
30 V	14 mΩ @ 4.5 V	36 A	





WDFN8 (μ8FL) CASE 511AB



4C13 = Specific Device Code A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]		
NTTFS4C13NTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel		
NTTFS4C13NTWG	WDFN8 (Pb-Free)	5000 / Tape & Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

3. This is absolute maximum rating. Parts are tested at T_J = 25°C V_{qs} = 10 V, $I_L = 15 \text{ Apk}, E_{AS} = 11 \text{ mJ}.$

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	5.8	
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	60.8	°C/W
Junction-to-Ambient - Steady State (Note 5)	$R_{ heta JA}$	160	°C/VV
Junction-to-Ambient - (t ≤ 10 s) (Note 4)	$R_{ heta JA}$	33.5	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS						•	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu A$		30			V
Drain-to-Source Breakdown Voltage (transient)	V _{(BR)DSSt}	V _{GS} = 0 V, I _{D(aval)} = TBD A, T _{case} = 25°C, t _{transient} = 100 ns		34			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				14.9		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1.0	μА
		V _{DS} = 24 V	T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS}	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 250 \mu A$		1.3		2.1	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				4.8		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		7.5	9.4	mΩ
		V _{GS} = 4.5 V	I _D = 12 A		11.2	14	
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 15 A			40		S
Gate Resistance	R_{G}	T _A = 25°C			1.0		Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				770		1
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			443		pF
Reverse Transfer Capacitance	C _{RSS}				127		
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15	5 V, f = 1 MHz		0.165		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			7.8		
Threshold Gate Charge	Q _{G(TH)}				1.4		nC
Gate-to-Source Charge	Q_{GS}				2.9		
Gate-to-Drain Charge	Q_{GD}				3.7		
Gate Plateau Voltage	V _{GP}				3.6		V
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 1		15.2		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 6. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

- 7. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	lote 7)				•		
Turn-On Delay Time	t _{d(ON)}				9		
Rise Time	t _r	V _{GS} = 4.5 V, V _{DS}	s = 15 V,		35		1
Turn-Off Delay Time	t _{d(OFF)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			13		ns
Fall Time	t _f				5		
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 10 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			6.0		ns
Rise Time	t _r				26		
Turn-Off Delay Time	t _{d(OFF)}				16		
Fall Time	t _f			3.0			
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V_{SD}	$V_{GS} = 0 V,$ $T_{J} = 25^{\circ}C$			0.82	1.1	.,
			T _J = 125°C		0.69		\ \
Reverse Recovery Time	t _{RR}	V_{GS} = 0 V, dIS/dt = 100 A/ μ s, I _S = 30 A			23.4		ns
Charge Time	t _a				12.1		
Discharge Time	t _b				11.3		
Reverse Recovery Charge	Qpp			9.7		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

6. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

7. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

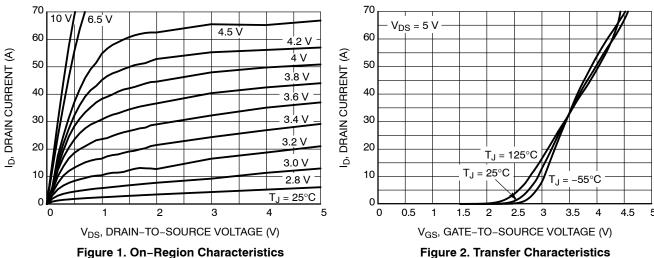


Figure 1. On-Region Characteristics

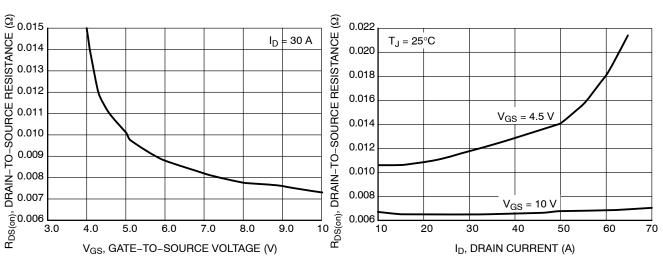


Figure 3. On-Resistance vs. V_{GS}

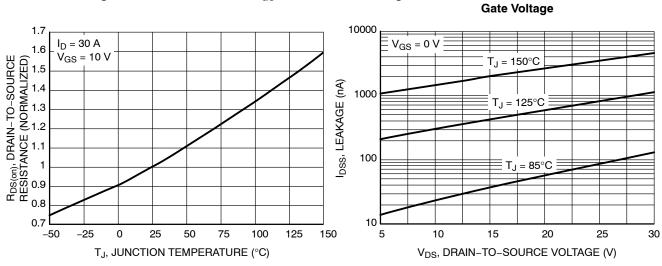


Figure 5. On-Resistance Variation with **Temperature**

Figure 6. Drain-to-Source Leakage Current vs. Voltage

Figure 4. On-Resistance vs. Drain Current and

TYPICAL CHARACTERISTICS

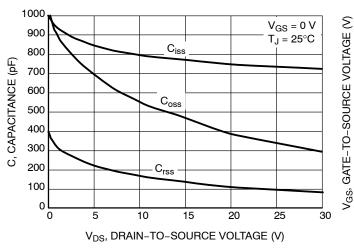


Figure 7. Capacitance Variation

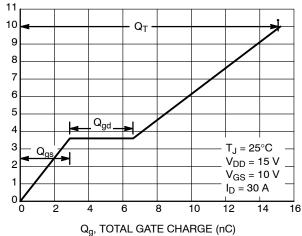


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

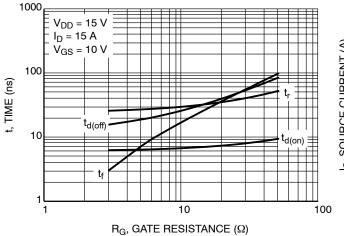


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

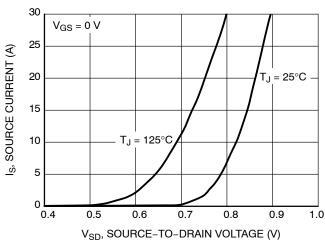


Figure 10. Diode Forward Voltage vs. Current

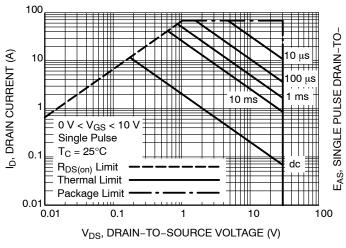


Figure 11. Maximum Rated Forward Biased Safe Operating Area

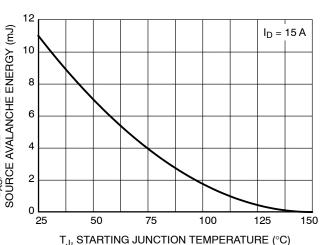


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

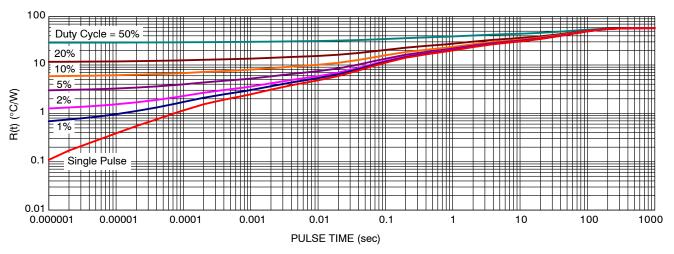


Figure 13. Thermal Response

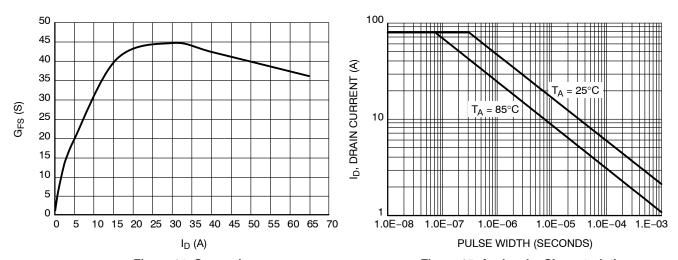
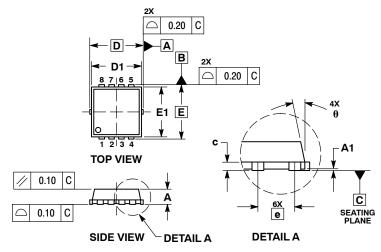


Figure 14. G_{FS} vs. I_D Figure 15. Avalanche Characteristics

PACKAGE DIMENSIONS

WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

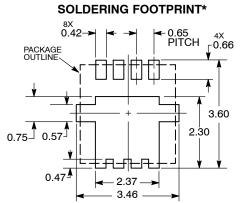


NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
C	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		C	.130 BSC	;	
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
Е		3.30 BSC		0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е		0.65 BSC	;	(0.026 BS	0	
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
М	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	

С В 0.10 Α 0.05 С e/2 E2 F3 D2 G **BOTTOM VIEW**



DIMENSION: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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